

Notice of References Cited	Application/Control No. 10/063,968	Applicant(s)/Patent Under Reexamination DEBOER ET AL.	
	Examiner Van Kim T. Nguyen	Art Unit 2151	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,754,702	06-2004	Kennelly et al.	709/223
	C	US-6,728,766	04-2004	Cox et al.	709/220
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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